

ANNUAL JOURNAL

OF

ELECTRONICS



Technical University of Sofia



Faculty of Electronic Engineering and Technologies

ANNUAL JOURNAL OF ELECTRONICS

EDITOR'S BOARD

President: Vice President: Members: Prof. Dr. Racho Ivanov Prof. Dr. Marin Hristov Prof. Dr. Stefan Ovcharov Prof. Dr. Georgy Mihov Assoc. Prof. Dr. Petar Yakimov

The Journal is issued by the FACULTY OF ELECTRONIC ENGINEERING AND TECHNOLOGIES, TECHNICAL UNIVERSITY of SOFIA, BULGARIA.

The Journal includes the selected papers from the International Scientific Conference Electronics '12, held on 19 - 21 September 2012 in Sozopol, Bulgaria.

© 2012 Faculty of Electronic Engineering and Technologies, Technical University of Sofia, Bulgaria.



ANNUAL JOURNAL

OF

ELECTRONICS



Technical University of Sofia



Faculty of Electronic Engineering and Technologies

ANNUAL JOURNAL OF ELECTRONICS

EDITOR'S BOARD

President: Vice President: Members: Prof. Dr. Racho Ivanov Prof. Dr. Marin Hristov Prof. Dr. Stefan Ovcharov Prof. Dr. Georgy Mihov Assoc. Prof. Dr. Petar Yakimov

The Journal is issued by the FACULTY OF ELECTRONIC ENGINEERING AND TECHNOLOGIES, TECHNICAL UNIVERSITY of SOFIA, BULGARIA.

The Journal includes the selected papers from the International Scientific Conference Electronics '12, held on 19 - 21 September 2012 in Sozopol, Bulgaria.

© 2012 Faculty of Electronic Engineering and Technologies, Technical University of Sofia, Bulgaria.

CONTENTS

BOOK 1

Levkov Ch. L., Single Lead ECG Recording/Monitoring Device for Home or Working Environment: a Critical Review	1
Mihov G. Sl., Subtraction Method for Powerline Interference Removal from	4
ECG in Case of Interference Amplitude Deviation	
Dobrev D. P. and T. D. Neycheva, Simple Two-Electrode Bootstrapped Non- Differential Biopotential Amplifier	8
Dobrev D. P. and T. D. Neycheva, Increased Power-Line Interference	12
Rejection by a Stray Capacitance Drive	12
Manoeva M. D., S. D. Tabakov and I. Ts. Iliev, AAL – Software Tool	16
Applicable in Assistive Systems for Elderly and Disable People	10
Tabakov S. D., I. Ts. Iliev and V. D. Manoev, Multipoint Emergency	19
Notification System	
Krasteva V. Tz., I. I. Jekova, E. G. Trendafilova, S. Ménétré, Ts. N. Mudrov and JPh. Didon, Transthoracic Impedance Cardiogram Indicates for Compromised Cardiac Hemodynamics in Different Supraventricular	23
and Ventricular Arrhythmias	27
Jekova I. I., V. Tz. Krasteva, G. Zh. Georgiev, L. P. Todorova, P. M. Vassilev and M. G. Matveev, Measurements on Ventilatory Signals during	21
Volume Controlled and Pressure Support Ventilation to Predict the	
Weaning Outcome	
Dotsinsky I. A., An Approach to the Chest Electrode Interchange Detection:	31
Preliminary Results	
Bogomilov M., G. Mitev, M. Mitev, St. Nikolov, P. Petrova, L. Tsankov, R.	34
Tsenov, G. Vankova-Kirilova, G. Zhelyazkov, High Energy Cosmic	
Rays Detection by Bulgarian Extensive Air Showers Array (BEASA)	
Part I. Physical Background	26
Bogomilov M., G. Mitev, M. Mitev, St. Nikolov, P. Petrova, L. Tsankov,	36
R.Tsenov, G. Vankova-Kirilova, G. Zhelyazkov, High Energy Cosmic	
Rays Detection by Bulgarian Extensive Air Showers Array (BEASA)	
Part II. Time and Amplitude Dependencies of the Signals on the	
Geometry of the Detector Cluster	40
Bogomilov M., G. Mitev, M. Mitev, St. Nikolov, P. Petrova, L. Tsankov, R. Tsenov, G. Vankova-Kirilova, G. Zhelyazkov, High Energy Cosmic	40

- Rays Detection by Bulgarian Extensive Air Showers Array (BEASA)
 Part III. Capture and Processing of the Detector Output Signals
 Peuteman J., J. Mareček, G. Vandecasteele and J.-J. Vandenbussche, 44
 Controlling a SIMATIC S5 Automated Pick and Place Machine Using a SIMATIC S7 PLC
- Bilcke M., H. Naert, S. Verslype, E. Blomme and R. De Craemer, Modular 48 Multichannel Air-coupled Ultrasonic Quality Control

- Ottoy G., S. Depoorter, N. Warlop, J.-P. Goemaere and L. De Strycker, 52 Evaluation of a Secure Authentication Protocol for Access Control over Near Field Communication
- Kokolanski Z., Cv. Gavrovski, M. Makraduli and Vl. Dimcev, Simple 56 Interface for Resistive and Capacitive Sensors Based on Time Interval Modulation
- Wang G., A. Heidari and G.C.M. Meijer, A Temperature Sensor with Dutycycle-modulated Output Implemented in CMOS Technology 59
- Foruhi S., M. Mohammadi, A. Heidary, G.C.M. Meijer and G. Wang, 61 Bandwidth Requirements for Op-amp in Temperature Sensors with Duty-cycle Modulated Output
- Cheng Y. and Stoyan Nihtianov, An Energy-Efficient Capacitive-Sensor 65 Interface Based on A Multi-Slope Modulator
- Nikolov G. T. and B. M. Nikolova, Resistor Temperature Coefficients 69 Extraction Using myDAQ
- Nikolov G. T., F. T. Koparanov, M. H. Tzanov and E. D. Manolov, 73 Measurement of Soil Moisture Using Wi-Fi DAQ
- Lazarov Ts. N. and T. St. Djamiykov, CMOS Image Sensors for Measuring 77 Applications
- Lazarov Ts. N. and T. St. Djamiykov, Methods for Increasing the 81 Performance of Image Processing System
- Marinov M. B., B. T. Ganev and R. V. Ivanoff, Implementation of Innovative 85 Air Conditioning System Using Power over Ethernet Sensor Nodes
- Marinov Ts. M., M. G. Mitev and G. G. Zhelyazkov, Electrostatic Field 89 Measurement Using Charge Sensing Amplifier
- Kolev I. St. and E. N. Koleva, Generators of Continuous Rectangular Pulses 93 with Digital Optron Integrated Circuits
- Kolev I. St. and E. N. Koleva, Generators of Single Pulses with Digital 97 Optron Integrated Circuits
- Kolev D. R., V. D. Todorova and B. H. Bodzhilov, Interface Control Circuits 101 for Piezoelectric Resonance Sensor Arrays
- Spirov D. St. and G. I. Ivanov, Monitoring System for Measuring Electrical 104 Quantities of the Induction Machine Drive
- Kolev K. I., A DSP System for Objective Quality Evaluation of Ready-to- 108 cook Minced Meat Products
- Peuteman J., J.-J. Vandenbussche, Stability Analysis of a Microgrid System 112 with a Constant Power Load
- Peuteman J., T. Verbeerst, P. Vansieleghem, J. Knockaert, D. Pissoort and J.-J. Vandenbussche, Reducing Electromagnetic Emitted Disturbances of an Adjustable Speed Drive System
- Popov E. I., L. I. Pindeva and St. T. Tsolov, Three Dimensional 120 Characteristics of A Current - Fed Parallel R L C Inverter Controlled by the Inverter Angle
- Arnaudov D. D., N. L. Hinov, N. R. Ranguelov, G. V. Kraev and N. P. 124 Gradinarov, Multiphase Current Source
- Kraev G. V., N. L. Hinov, D. D. Arnaudov, N. R. Ranguelov and N. P. 128

Gradinarov, Multiphase DC-DC Converter with Improved Characteristics for Charging Supercapacitors and Capacitors with Large Capacitance

Goranov P. T., Current Fed Inverter Current Source Supplied	132
Stanchev T. Pl., Y. Avenas and Y. H. Berrouche, Realisation of a Test Bed for the Test of a Cooling System Activated by an Electro-Osmotic	136
Pump	
Vuchev A. St., N. D. Bankov and Y. K. Madankov, Current Control for a	140
CO2 Laser using LCC Resonant DC-DC Converter	
Gerazov B. and Z. Ivanovski, The Influence of the Number of States in Whole	144
Word HMMs on ASR Performance	1.40
Kostov M., M. Petkovski and I. Jolevski, Images Pseudo-hash by Using Wavelet Coefficients	148
Kukenska V. St., P. B. Minev and I. Ts. Varbov, Hardware Implementation of	152
Algorithm for Flash Memory Testing	132
Lakov L. I., V. St. Popova, K. A. Toncheva and St. N. Asenov, Technological	156
Aspects and Control in Obtaining Large Piezoceramic Cylinders for	100
Underwater Acoustic Transducers	
Stefanova St. A., Time Series Prediction Using Linear Neural Networks	160
Todorov T. G., Simulink Modelling and Design of FPAA Prototype for	164
Studying of Modified Van der Pol Equation	
Gerganska T. V., M. H. Hristov, Vl. E. Grozdanov and R. I. Radonov,	168
Visualization and Data Analysis in R Project	
Kotsev I. N., M. H. Hristov and VI. E. Grozdanov, Provision of Firmware for	171
3D Kinematic Analysis System	
Popova P. P., E. D. Gadjeva and Vl. E. Grozdanov, Development of	174
Computer Software for Processing and Visualization of Data Obtained	
from MEMS Acceleration Sensors	
Gadjeva E. D. and D. G. Gaydazhiev, Effectiveness Increasing of SPICE RF	178
Inductor Models	
Gadjeva E. D., D. Y. Shikalanov and G. G. Valkov, An Approach to Model	182
Parameter Extraction of Photovoltaic Module	
Angelov Pl. A., Analysis of the Methods to Define the Switching Losses in	186
Class D Audio Amplifier	
Asparuhova K. K., Ts. N. Lazarov and I. Sl.Spasov, Programmable Modular	190
System for Current Source Signal Processing	

INDEX

A 1 . 1 1	M	D	10.00
Aleksandrova	Mariya	Petrova	b2 p66
Anastasova	Teodora	Georgieva	b2 p109
Andonova	Anna	Vladova	b2 p51,55,59
Angelov	George	Vasilev	b2 p35,39
Angelov	Plamen	Angelov	b1 p186
Arnaudov	Dimiter	Damyanov	b1 p124,128
Asenov	Stanislav	Nikolov	b1 p156
Asparuhova	Katya	Konstantinova	b1 p190
Atanasov	Boris	Petkov	b2 p35
Avenas	Yvan		b1 p136
Badarov	Dimiter	Hristov	b2 p173
Bahchedjiev	Christo	Petkov	b2 p105
Bankov	Nikolay	Dimitrov	b1 p140
Bankova	Ana	Gabrielova	b2 p49
Berrouche	Youcef	Hichem	b1 p136
Bilcke	Mattias		b1 p48
Blomme	Erik		b1 p48
Bodzhilov	Bozhidar	Hristov	b1 p101
Bogdanov	Lubomir	Valeriev	b2 p181
Bogomilov	Mariyan		b1 p34,36,40
Botev	Martin	Atanasov	b2 p201
Bouras	Mounir		b2 p70
Boydens	Jeroen		b2 p149,153,157
Bozhilov	Ivan	Asenov	b2 p137
Brusev	Tihomir	Sashev	b2 p91,185
_			
Catteeuw	Wim		b2 p153
Chaban	Ostap	Volodymtrovych	b2 p95
Chayleva	Irina	Kirilova	b2 p201
Cheng	Yao		b1 p65
Cholakova	Tetiana	Mihailova	b2 p105
Cordemans	Piet		b2 p149,153
Coudyzer	Gertjan		b2 p161
Craemer	Renaat	De	b1 p48, b2 p23
Delibozov	Nikolay	Georgiev	b2 p63
Denishev	Krassimir	Hristov	b2 p113
Depoorter	Sven		b1 p52
Didon	Jean-Philippe		b1 p23
Dilov	Kristian	Dilov	b2 p189
Dimcev	Vladimir		b1 p56
Dimitrov	Georgi		b2 p121
Dimitrov	Emil	Nikolov	b2 p189
			L

Djamiykov Dobrev Dobreva Dotsinsky Duan	Todor Dobromir Verginiya Ivan	Stoianov Petkov Plamenova Assenov Guoyong	b1 p77,81 b1 p8,12 b2 p201 b1 p31 b2 p9,15
Fechan Foruhi	Andrij S.	Vasyljovych	b2 p95 b1 p61
Gadjeva Ganev Gavrovski Gaydazhiev Georgiev Georgiev Gerazov Gerganska Gieva Goemaere Goranov Goranova Gradinarov Grancharova Grozdanov	Elisaveta Borislav Cvetan Dobromir Georgi Branislav Teodora Elitsa Jean-Pierre Peter Mariana Nikola Nely Vladimir	Dimitrova Todorov Georgiev Ognyanov Zheliazkov Velichkova Emilova Trifonov Evstatieva Petrov Stanislavova Emilov	b1 p174,178,182 b1 p85 b1 p56 b1 p178, b2 p27, 113 b2 p27 b1 p27 b1 p144 b1 p168 b2 p31,35 b1 p52, b2 p161 b1 p132 b2 p125,129,141 b1 p124,128 b2 p177 b1 p168,171,174
Heidari Hinov Hocini Hotra Hristov	A. Nikolay Abdesselam Zenon Marin	Lyuboslavov Yuriyovych Hristov	b1 p59,61 b1 p124,128 b2 p70 b2 p78,95,99,103 b1 p168,171 b2 p23,35,39,63
Iliev Ivanoff Ivanov Ivanov Ivanov Ivanovski	Ivo Radoslav Juriy Racho Georgi Zoran	Tsvetanov Velichkov Ivov Marinov Ivanov	b1 p16,19 b1 p85 b2 p19 b2 p181 b1 p104 b1 p144
Jekova Jolevski	Irena Ilija	Ilieva	b1 p23,27 b1 p148
Kadijski Kakanakov Kamenov Khorev	Georgi Roumen Svetoslav Vladimir	Boykov Davidkov Sergeev	b2 p113 b2 p105 b2 p145 b2 p74

Kireva	Teodora	Todorova	$h^{2} = 160$
Knockaert	Jos	Todorova	b2 p169
			b1 p116
Kokolanski Kolaklieva	Zivko	Detrovio	b1 p56
	Lilyana	Petrova	b2 p105
Kolev	Georgi	Dobrev	b2 p88, 113
Kolev	Ivan	Stanchev	b1 p93,97
Kolev	Dimo	Rumenov	b1 p101
Kolev	Krassimir	Iliev	b1 p108
Koleva	Elena	Nedyalkova	b1 p93,97
Koparanov	Filip	Todorov	b1 p73
Kostamovaara	Juha		b2 p9,15
Kostiv	Nataliya	Volodymyrivna	b2 p103
Kostov	Mitko		b1 p148
Kotsev	Ivan	Nikolaev	b1 p171
Kraev	George	Vassilev	b1 p124,128
Krasteva	Vessela	Tzvetanova	b1 p23,27
Krumova	Milena	Yordanova	b2 p117
Kukenska	Valentina	Stoyanova	b1 p152
Lakov	Lyuben	Ivanov	b1 p156
Landschoot	Sille	Van	b2 p157
Lausnay	Steven	De	b2 p161
Lazarov	Tsvetomir	Nikolov	b1 p77,81,190
Levkov	Chavdar	Lev	b1 p1
Madankov	Yasen	Kostadinov	b1 p140
Makraduli	Mario		b1 p56
Manoev	Ventsyslav	Draganov	b1 p19
Manoeva	Mariana	Dimitrova	b1 p16
Manoilov	Peter	Georgiev	b2 p165
Manolov	Emil	Dimitrov	b1 p73, b2 p23
Mareček	Jakub		b1 p44
Marinov	Marin	Berov	b1 p85
Marinov	Tsvetan	Miroslavov	b1 p89
Matveev	Mikhail	Georgiev	b1 p27
Meijer	G.C.M.	-	b1 p59,61
Ménétré	Sarah		b1 p23
Mihov	Georgy	Slavchev	b1 p4, b2 p173
Minev	Petar	Borisov	b1 p152
Mitev	Rosen	Slavov	b2 p121
Mitev	George		b1 p34,36,40
Mitev	Mityo	Georgiev	b1 p34,36,40,89
Mitov	Kiril	Malenkov	b2 p137
Mohammadi	M.		b1 p61
Mudrov	Tsvetan	Nikolaev	b1 p23
Mykytyuk	Zenoviy	Matviyovych	b2 p95,99
ing hy ty un	y	1,1ut + 1 y 0 + y 011	0- p/0,//

Naert Naydenov Nesteruk Neycheva Nihtianov Nikolov Nikolov Nikolov Nikolov	Hans Teodor Denis Tatyana Stoyan Dimitar Stoyan Georgi Boyanka	Borislavov Dimitrova Nikolov Todorov Marinova	b1 p48 b2 p165 b2 p74 b1 p8,12 b1 p65 b2 p23 b1 p34,36,40 b1 p69,73 b1 p69, b2 p185
Ottoy Ozturk	Geoffrey Ayhan		b1 p52 b2 p66
Pandiev Pashinski Peev Petkovski Petrov Petrova Petryshak Peuteman Pindeva	Ivailo Chavdar Pavel Mile Boyko Petia Vasyl Joan Liliya	Milanov Ognyanov Biserov Baev Stepanovych Ivanova	b2 p133 b2 p105 b2 p129 b1 p148 b2 p197,201 b1 p34,36,40 b2 p99 b1 p44, 112,116 b1 p120
Pissoort Popov Popova Popova	Davy Evgeniy Veneta Petya	Ivanov Stoyanova Petrova	b1 p116, b2 p23 b1 p120 b1 p156 b1 p174
Radev Radonov Ranguelov Raykov Rusev	Aleksandar Rosen Nikolai Kiril Rostislav	Petkov Ivanov Ranguelov Toshkov Pavlov	b2 p55 b1 p168, b2 p46,63 b1 p124,128 b2 p43 b2 p35
Serbezov Shikalanov Shindov Shoikova Shoikova Shymchyshyn Smatko Spasov Spasov Spasov Spasov Spasova Spasova Spirov Spirov	Valery Dimitar Petar Elena Olga Vasilii Georgi Grisha Ivan Mariya Rosen Dimitar	Stojanov Yordanov Christov Dikova Yosypivna Spasov Valentinov Slavov Lyubomirova Petrov Stoilov	b2 p109 b1 p182 b2 p109 b2 p117 b2 p99 b2 p109 b2 p80,84 b2 p193 b1 p190 b2 p39 b2 p177 b1 p104

Stanchev Stankulov	Todor Kaloyan Eric	Plamenov Vitkov	b1 p136 b2 p55 b2 p140 157
Steegmans Stefanova	Stela	Angelova	b2 p149,157 b1 p160
Steven	Nobby	1 mgelovu	b2 p161
Stoimenov	Eltimir	Chavdarov	b2 p133
Stoyanov	Rumen	Yordanov	b2 p19
Stoyanova	Lyudmila	Jordanova	b2 p125,129
Strycker	Lieven	De	b1 p52, b2 p161
Sushynskyy	Orest	Yevgenovych	b2 p95,99
~~~~ <u></u>		8	F
Tabakov	Serafim	Dimitrov	b1 p16,19
Tchoumatchenko	Vassiliy	Platonovitch	b2 p141
Todorov	Todor	Georgiev	b1 p164
Todorova	Lyudmila	Pavlova	b1 p27
Todorova	Velimira	Dimitrova	b1 p101, b2 p145
Toncheva	Antonova	Krasimira	b1 p156
Toteva	Ina	Plamenova	b2 p51
Trendafilova	Elina	Georgieva	b1 p23
Tsankov	Ludmil	e	b1 p34,36,40
Tsenov	Roumen		b1 p34,36,40
Tsolov	Stoyan	Toshev	b1 p120
Tzanov	Petko	Nikolaev	b2 p177
Tzanov	Mihail	Hristov	b1 p73
Uzunov	Ivan	Stefanov	b2 p27
Vainshtein	Sergey		b2 p9,15
Valkov	Georgi	Georgiev	b1 p182
Vandecasteele	Geert	Georgiev	b1 p44
Vandenbussche	Jean-Jacques		b1 p44, 112,116
Vankova-Kirilova	Galina		b1 p34,36,40
Vansieleghem	Pieter		b1 p116
Varbov	Ilian	Tsvyatkov	b1 p152
Vasileva	Tania	Krumova	b2 p141
Vassilev	Peter	Mladenov	b1 p27
Vavilov	Vladimir	whatehov	b2 p1,74
Verbeerst	v laulilli		
	Tommy		-
Verslyne	Tommy Sammy		b1 p116
Verslype Videkov	Sammy	Hristov	b1 p116 b1 p48
Videkov	Sammy Valentin	Hristov	b1 p116 b1 p48 b2 p43,46,49
Videkov Vincke	Sammy Valentin Robbie		b1 p116 b1 p48 b2 p43,46,49 b2 p157
Videkov Vincke Volynyuk	Sammy Valentin Robbie Dmytro	Yuriyovych	b1 p116 b1 p48 b2 p43,46,49 b2 p157 b2 p103
Videkov Vincke Volynyuk Voznyak	Sammy Valentin Robbie Dmytro Lesya	Yuriyovych Yuriivna	b1 p116 b1 p48 b2 p43,46,49 b2 p157 b2 p103 b2 p78
Videkov Vincke Volynyuk	Sammy Valentin Robbie Dmytro	Yuriyovych	b1 p116 b1 p48 b2 p43,46,49 b2 p157 b2 p103

Warlop	Nick		b1 p52
Yordanov	Rumen	Stoyanov	b2 p19,121
Zhelyazkov	Georgi		b1 p34,36,40, 89

# Resistor Temperature Coefficients Extraction Using myDAQ

Georgi Todorov Nikolov and Boyanka Marinova Nikolova

*Abstract* - Resistor temperature coefficients, play an important role in electronic circuits design and sizing, where often the worst case operating condition dictates the design. This paper describes method for direct measurement of the temperature coefficients of the resistor using low cost module myDAQ and possibility of virtual instrumentation. The main objective of present work is to demonstrate how with virtual instrumentation can be solved some difficult engineering problems such as temperature coefficients measurement and model parameters extraction.

*Keywords* – LabVIEW, myDAQ, resistor temperature coefficients, SPICE simulation

### I. INTRODUCTION

For the design of electronic devices and instruments, designers select passive components with specific base parameters' values. This values dependents on the length, cross sectional area of the material they are made from. The quoted value of however is actually given at a particular temperature, because the temperature of the component also affects its value [1].

For this reason, designers also must make sure the parameter value doesn't change too much when the temperature changes. The change in resistance or capacitance due to a change in temperature is normally quite small over a particular temperature range. This is because the manufacturer has chosen a material having a characteristics not greatly influenced by temperature. However, to ensure parameter change is minimized, designers measure and calculate the change in component value for a change in temperature value and obtain the Further temperature coefficients. this temperature coefficients can be used to predict behaivior of the component versus temperature changes using simulation procedures.

In this work a general applicable method for direct extraction of the resistor temperature coefficients is presented. For temperature sensing element a platinum resistive temperature detector is choosen. As measurement device is selected National Instrument's myDAQ, which is modular device with USB connection to the computer platform. One of the benefits of using National Instruments boards is the availability of DAQmx drivers for the measurement hardware. The other benefit is that myDAQ

¹Georgi Nikolov is from the Faculty of Electronic Engineering and Technologies at Technical University of Sofia, 8 Kl. Ohridski Blvd, Sofia 1000, Bulgaria, E-mail: gnikolov@tu-sofia.bg.

²Boyanka Nikolova is from the Faculty of Telecommunications at Technical University of Sofia, 8 Kl. Ohridski Blvd, Sofia 1000, Bulgaria. E-mail: bnikol@tu-sofia.bg.

is part of National Instruments circuits teaching solution. The circuits teaching solution is the complete platform of software, hardware, and courseware for educators to build student expertise through practical application in design, prototyping, and testing of electronic circuits [4]. In this environment, students should be able to compare the results of a simulated and real measured data in the same time.

### II. RESISTOR TEMPERATURE COEFFICIENTS

By definition the temperature coefficient TCX is the relative change of a physical property X by changing the temperature T. Therefore [1]:

$$TCX = \frac{dX}{X.dT}, \,^{\circ}C^{-1} \text{ or } K^{-1}.$$
 (1)

For the linear temperature dependences, *TCX* is constant and the physical property can be calculated by:

$$X(T) = X(T_{ref})(1 + TCX.\Delta T), \qquad (2)$$

where  $T_{ref}$  is the reference temperature, and  $\Delta T$  is the difference between *T* and  $T_{ref}$ .

For quantities that vary polynomially, exponentially or logarithmically with temperature, it can be used more than one temperature coefficients for a useful approximation for a certain range of temperatures.

The temperature coefficient of resistance is a number used to predict how the resistance of a material changes with changes in temperature. The electronic manufacturer has chosen a materials with low temperature coefficient and so the resistor has a low temperature coefficient as well. Therefore the change in resistance due to a change in temperature is normally quite small over a particular temperature range. This change in value is normally quoted in parts per million (ppm).

The change in value of a resistor with changing temperature is not very dependent on changes in the dimensions of the component as it expands or contracts due to temperature changes. It is due mainly to a change in the resistivity of the material caused by the activity of the atoms of which the material is made.

A resistor's temperature behavior can be precise described using its temperature coefficients TC1 and TC2, which are derived from the Taylor Series expansion around the nominal temperature  $T_{ref}$  [2]:

$$R(T) = R(T_{ref}) \left[ 1 + TC1(T - T_{ref}) + TC2(T - T_{ref})^2 \right] .$$
(3)

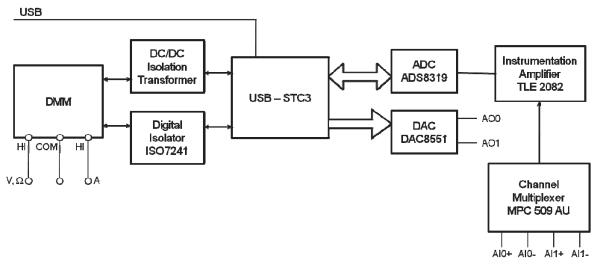


Fig. 1. The part of myDAQ subsystems

### III. MYDAQ

National Instruments myDAQ is a portable data acquisition device that uses LabVIEW based software. The myDAQ is designed primary for students, allowing them to measure and analyze real-world signals. This portable data acquisition system is ideal for exploring electronics and taking sensor measurements and offers an affordable and for students to make accessible way electrical measurements, control electronics systems, and experience the world through instrumentation [4, 5]. Within a single plug-and-play USB device, the myDAQ combines portability with a suite of number of the most commonly used instruments in the educational laboratory. Integrated circuits supplied by Texas Instruments form the power and analog modules of myDAQ. In the Figure 1 is shown the arrangement and function of the part of myDAQ subsystems.

The ADS8319 is 16-bit analog-to-digital converter. Device includes a capacitor based, successive approximation ADC with inherent sample and hold. The ADS8319 unipolar single-ended input range supports an input swing V to  $V_{ref}$ . Device operation is optimized for very low power operation. This feature makes it attractive for lower speed applications.

The TLE2082 is JFET-input operational amplifier. It has wide supply-voltage rails up to  $\pm 19$  V. On-chip zener trimming of offset voltage yields greater accuracy in dc-coupled applications. This makes this amplifier good suited for interfacing with high-impedance sensors or very low level ac signals.

The MPC509AU is a 4-channel differential multiplexer. Analog input voltages may exceed either power supply voltage without disturbing the signal path of other channels. These features make the MPC509A ideal for use in systems where the analog signals originate from external equipment or separately powered sources.

In general, the myDAQ provides two differential analog inputs, two analog outputs, eight digital inputs and outputs, audio input and output, DC power supplies, and digital multimeter (DMM) functions [4]. The DMM provides the functions for measuring voltage (DC and AC), current (DC and AC), resistance, and diode voltage drop. It is important to notice that DMM measurements are software-timed, so update rates are affected by the load on the computer and USB activity.

### IV. EXPERIMENTAL SETUP

#### A. Hardware Design

The idea how to investigate resistor's temperature behavior using myDAQ is illustrated in fig. 2. In order to measure continuous temperature close up investigated resistor a resistance temperature detector (RTD) is used. Resistance temperature detectors rely on the principle that the resistance of a metal increases with temperature. When made of platinum and when specified to have a resistance of 100  $\Omega$  at 0°C, they are known as Pt100. Each RTD requires the data acquisition hardware to provide a constant current source. The current flows through the RTD and the voltage drop over the RTD is measured. Using Ohms law the value of the resistance of the RTD can be calculated.

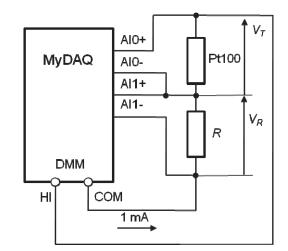


Fig. 2. Experimental setup

The capability of digital multimeter (DMM) build in myDAQ to produce reference current is used in presented circuit. The Pt100 is wired in a circuit as a resistor. It requires a positive input on one side and a negative input on the other side. As can be seen in the figure resistors are arranged in a chain, so the current has only one path to take. The current is the same through each resistor. The total resistance of the circuit is found by simply adding up the resistance values of the individual resistors. When the current is passed through the resistive devices it produce a voltages that can be sensed by a data acquisition system. The level of each voltage output signal will depend directly on the resistance and magnitude of the current excitation source.

Because myDAQ analog inputs have large input impedance (10 G $\Omega$ ), any voltage dropped across the main current-carrying wires will not be measured by the DAQ analog inputs, and so do not factor into the resistance calculation at all. In such a way the measurement method introduced in this work avoids errors caused by wire resistance.

#### B. Software Design

In order to be controlled with LabVIEW, myDAQ requires ELVISmx and DAQmx software drivers. Block diagram of introduced system for resistor's temperature behaviour investigation is shown in Fig. 3. The base DAQmx functions are used to control the measurement process. In the upper part of the block diagram are placed functions for DMM control. The DMM is configured for 2wire resistance measurament with 1 mA internal exitation current. For this measurement task, result is not needed and Read function absent. In lower part of the figure are placed functions for analog inputs control. Virtual analog channels are implemented by Create Channel function. Synchronization and timing are managed by Timing and Start Task functions. Inside the while loop on the left is the Read function. This function acquired measured data and it's configured to read multiple value from multiple channels each time it executes. All of the code inside the While Loop continues to run until the Stop button is pressed on the front panel. The Wait function delays execution of the while loop to every 100 ms. At the end of

the data flow the DAQmx Clear Task function and Simple Error Handler are placed.

Once a measurable voltage signals have been obtained these signals must be converted to actual units of temperature and resistance respectively.

The signal coming from the Pt100 is converted to a temperature using the polynomial equation from the Pt100 specifications and the Callendar-Van Dusen equation [1]. For  $T > 0^{\circ}C$ , the quadratic formula can be used to solve for temperature as a function of measured resistance with the result:

$$T_{R} = \frac{-R_{0}A + \sqrt{R_{0}^{2}A^{2} - 4R_{0}B(R_{0} - R_{T})}}{2R_{0}B}.$$
 (4)

where  $R_T$  is resistance at temperature T(°C),  $R_0$  is resistance at 0°C, T is temperature in °C, and the Callendar-Van Dusen constants A and B are obtained from actual resistance measurements. Common Callendar-Van Dusen constant values for Pt100 that are used in this investigation are:  $A = 3.908.10^{-3}$ ;  $B = -5.775.10^{-7}$ .

This equation is solved in LabVIEW using Formula node. Finally, it output the result to a file using Write To Spreadsheet File function.

### V. RESULTS AND SIMULATION

The approach for temperature measurement of resistance described above is implemented for metal film resistor with nominal value of 100  $\Omega$ .

Once the all resistance and temperature data is obtained and saved in file, this data can be manipulate with LabVIEW Regressin Solver function [3]. When starting the function a dialog window is opened urged the user to select the type of regression analyses to best fit the experimental data points to some equation. Regression is a process of constructing a mathematical function that has the best fit to a series of data points. This technique acts to minimize the sum of the squares deviations of the experimental values from values calculated using some theoretical equation. Solving the regression equation is difficult task but by using capability of virtual instrumentation in this development solving the regression equation is quite easy.

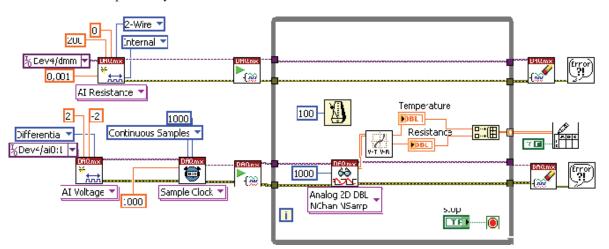


Fig. 3. Block diagram of the presented system

For this purpose the LabVIEW function called "Regression solver" is used with slight adaptation. The dialog window of regression solver is shown on the Fig. 4.

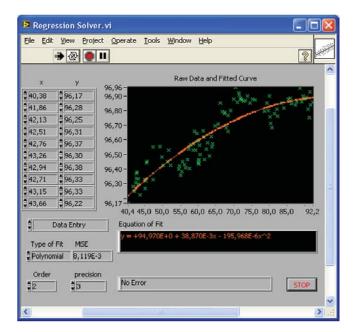


Fig. 4. The dialog window of regression solver

As can be seen from the figure acquired data is well described with the second degree polynomial equation:

$$y = a + b.x + c.x^2$$
. (5)

where a = 94.97,  $b = 38.87.10^{-3}$  and  $c = 195.968.10^{-6}$ .

The temperature coefficients *TC*1 and *TC*2 can be practically define using polynomial curve fitting procedure. Comparing equations (3) and (5), and assuming that  $T_{ref} = 0$ °C the coefficients are obtained as follows:

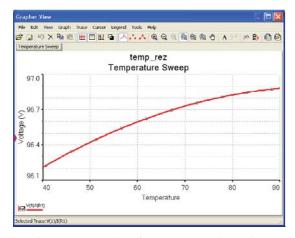
$$R(T_{ref}) = a,$$

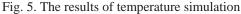
$$TC1 = \frac{b}{R(T_{ref})},$$

$$TC2 = \frac{c}{R(T_{ref})}.$$
(6)

The values for the temperature components according to (6) are  $R(T_{ref}) = 94.97 \ \Omega$  with coefficients of resistance  $TC1 = 0.4093.10^{-3} \ 1/^{\circ}C$  and  $TC2 = -2.06347.10^{-6} \ 1/^{\circ}C^{2}$ .

In order to complete the coefficients extraction process, obtained values are established in Multisim resistor model. Fig. 5 illustrates the simulation results of the temperature vs. resistance characteristic of metal film resistor, using the SPICE simulator. The error of the model is formed only from the accuracy of the curve fitting, because the characteristic is described by mathematical polynomial equation.





### VI. CONCLUSION

An approach to direct extraction of resistor temperature coefficients has been introduced in present paper. The aproach is applicable to any resistor with value between 100 ohms to 10 kohms. In order to build presented virtual system, the part of National Instruments circuits teaching solution platform has been used. It is integrated hardware and software that guides students through the engineering and design process from understanding circuit theory to developing and simulating designs to prototyping and validation. In presended work are included myDAQ for hardware and LabVIEW and Multisim for software. With the LabVIEW and myDAQ prototyping platforms, users and educators can quickly and easily develop their circuits and take measurements interactively in the laboratories using DAOmx instrumental drivers. On the other hand Multisim provides intuitive circuit design and SPICE simulation to help students explore circuit theory and investigate behavior of electronic compounents.

The presented approach can be applied for any electronic device with DAQs with reference current source to realize virtual system for temperature coefficients measurement. However to achieve better measurement accuracy the more precise current source and analog inputs must be used because in present development the accuracy and long term stability of these modules is not investigated.

### ACKNOWLEDGEMENT

This investigation has been carried out in the framework of the research project 122ΠД0041-07.

#### REFERENCES

[1] John G. Webster. *Electrical measurements, signal processing, and displays,* ISBN 0-8493-1733-9, CRC Press LLC, 2004.

[2] E. Dudek, M. Mosiadz, M. Orzepowski. *Uncertainties of resistors temperature coefficients*, Measurement Science Review, Volume 7, Section 1, No. 3, 2007.

[3] B. Nikolova, G. Nikolov. *Design, Development and Calibration of Virtual System for Relative Humidity Measurement.* Sensors & Transducers Journal, ISSN 1726-5479, Vol.93, Issue, 2008.

[4] National Instruments Corporation. *NI myDAQ User Guide and Specifications*, 2012.

[5] P. Blume. *The LabVIEW Style Book*, ISBN 0-13-145835-3, Pearson Education, 2007.